Electronic Supplementary Information: Understanding the size effects on the electronic structure of ThO₂ nanoparticles.

Lucia Amidani,^{a,b} Tatiana V. Plakhova,^c Anna Yu. Romanchuk,^c Evgeny Gerber,^{a,b,c} Stephan Weiss,^b Anna Efimenko,^d Christoph J. Sahle,^d Sergei M. Butorin,^e Stepan N. Kalmykov^c and Kristina O. Kvashnina^{a,b}

^a Rossendorf Beamline at ESRF – The European Synchrotron, CS40220, 38043 Grenoble Cedex 9, France.
^b Helmholtz Zentrum Dresden-Rossendorf (HZDR), Institute of Resource Ecology, PO Box 510119, 01314 Dresden, Germany.
^c Department of Chemistry, Lomonosov Moscow State University, Leninskie Gory 1/3, 119991, Moscow.
^d ESRF – The European Synchrotron, CS40220, 38043 Grenoble Cedex 9, France.
^e Molecular and Condensed Matter Physics, Department of Physics and Astronomy, Uppsala University, P.O. Box 516, Uppsala, Sweden.

HRTEM characterization:

The microstructure of ThO_2 samples was determined using high-resolution transmission electron microscopy (HRTEM) technique (Libra 200 by Carl Zess and a Jeol-2100F). Images were taken in transmission mode at magnifications up to 1000K at an accelerating voltage of 200 kV. The electron diffraction (ED) patterns were collected from a selected region of the sample. The analysis of the interplanar distances from the electron diffraction patterns was performed by comparing with the gold standard, taken at the same length of the chamber. To estimate the average particle size and distribution from HRTEM images, sets of > 200 particles were used.



Figure S1: Sample "2.5 nm" a) HRTEM image and b) ED pattern for ThO₂ NPs obtained by precipitation from 0.1 M Th(NO₃)₄ · 5H₂O and 3M NaOH as precipitants with the subsequent drying at 40 °C on air; c) size distributions of ThO₂ NPs as obtained from HRTEM data.



Figure S2: Sample "3.8 nm" a) HRTEM and b) ED data for ThO₂ NPs obtained by precipitation from 0.1 M Th(NO₃)₄ \cdot 5H₂O and 3M NaOH as precipitants with the subsequent drying at 150 °C on air; c) size distributions of ThO₂ NPs as obtained from HRTEM data.



Figure S3: Sample "5.8 nm" a) b) HRTEM and d) ED data for ThO₂ sample obtained by annealing thoria NPs at 400°C for 4 hours; d) size distributions of ThO₂ NPs as obtained from HRTEM data.



Figure S4: Sample "33.8 nm" a) HRTEM and b) ED data for ThO_2 sample obtained by annealing thoria NPs at 800°C for 4 hours; d) size distributions of ThO_2 NPs as obtained from HRTEM data.

| Database PCPDF for | Sample "2.5 nm" | Sample "3.8 nm" | Sample "5.8 nm" | Sample "33.8 nm" |
|-------------------------------|-----------------|-----------------|-----------------|------------------|
| ThO ₂ ¹ | | | | |
| 3.23 | 3.15 | 3.56 | 3.32 | 3.17 |
| 2.79 | 2.71 | 3.09 | 2.91 | 2.75 |
| 1.98 | 1.93 | 2.15 | 2.04 | 1.93 |
| 1.61 | 1.63 | 1.84 | 1.73 | 1.65 |
| 1.39 | | 1.49 | 1.45 | 1.36 |
| 1.28 | | 1.24 | 1.32 | 1.26 |
| 1.25 | | | 1.22 | 1.21 |

Table S1. Experimental and theoretical interplanar distances in Å for ThO₂ NPs, studied in the present work.

1. Holzer, J. & McCarthy, G. *ICDD Grant-in-Aid*, (North Dakota State University, Fargo, North Dakota, USA, 1991).